

Search Notes

Application/Control No.

10/822,664

Examiner

John Q. Nguyen

Applicant(s)/Patent under
Reexamination

KITAMURA ET AL.

Art Unit

3654

SEARCHED

Class	Subclass	Date	Examiner
242	348 348.2	6/22/05 ↓	JN ↓
360	132	↓	↓

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR